

TA660 Device Compliance Test User's Guide

Scope

The scope of this document is to familiarize the user with various sections of the Device Compliance Test where IUT interaction is required. This document should allow the user to prepare for these tests in advance.

Description

Compliance Test program includes three test categories which require interaction from IUT. These are DS_XX (device status test), MP_XX (General Component Protocol checklist of master) and 1.XX (Component Protocol checklist for a master device) tests. All other tests are performed automatically.

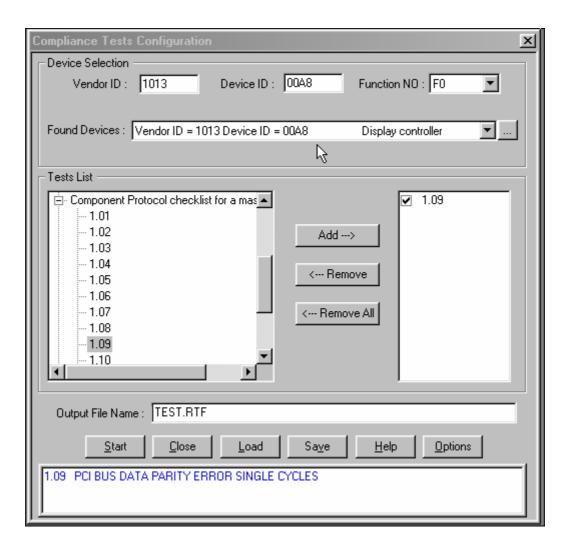
In these tests the TA660 is used as target and the IUT is the master. The TA660 as a target device needs to have three different addresses for Memory, I/O and Configuration spaces where master (IUT) can read and write to these addresses. These addresses must be free from use by other agents in the system therefore the TA660 software searches the system at the beginning of the compliance test and finds the addresses which TA660 can use. So long as the system under test has not changed configuration these addresses should stay the same for use for TA660 during the Device Compliance Test.

Most of the time the Memory address found for TA660 is at 0x10000000 and free I/O address is at 0x10000000. Please note this may change depending on system configuration and address assignment by the BIOS.

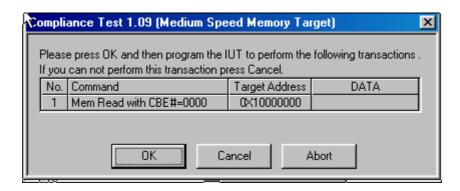
To find which addresses are free for TA660 as target in advance the user may select and execute test 1.09 (press cancel at each message not to execute the test if only verifying the address assignment for TA660).

In the example below all memory, I/O and Configuration addresses are all assigned to be 0x10000000



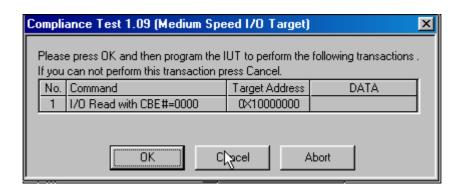


Test Selection menu

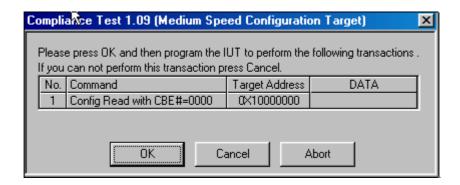


Memory address specified to be at 0x1000000





I/O address specified to be at 0x10000000



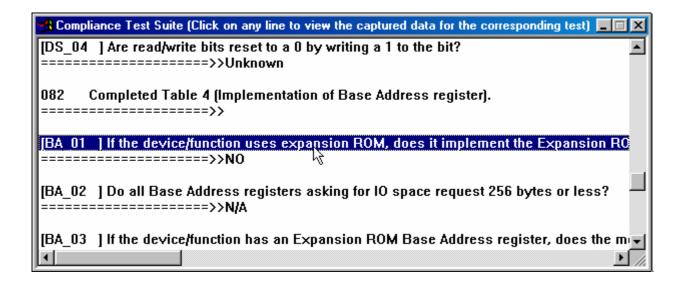
Configuration address specified to be at 0x10000000



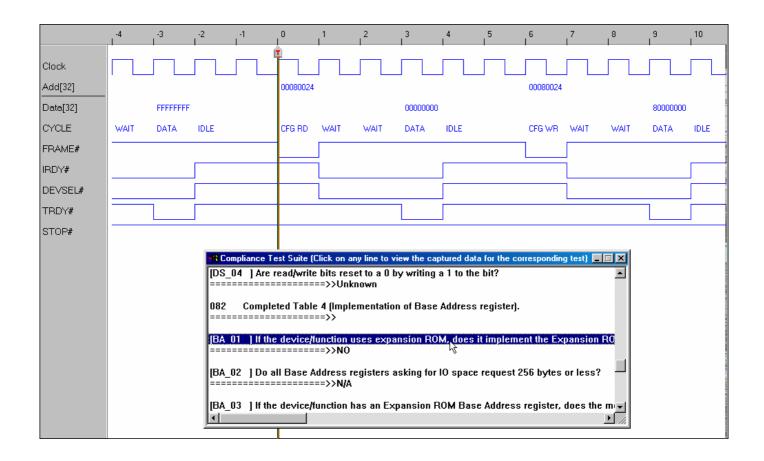
Pass/Fail

Pass/Fail of a test does not necessarily depend on Yes/No responses, some devices may be designed not to perform certain functions. Therefore the user must study the test response and compare it with its device specifications to see if it is okay or not.

In order to understand why TA660 reported a Yes or No response users may double click on the desired test title (on the screen display not the saved test report), BA-01 in this case, and a data display will open up corresponding to this test indicating the captured TA660 interaction with the IUT device. Most cases if the response has been No the trigger position will be on the transaction that has caused the No response.





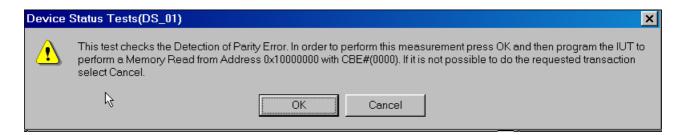




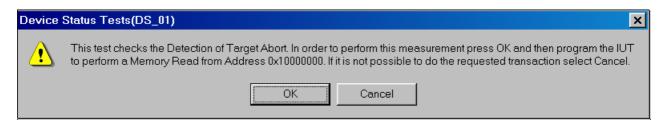
Tests

DS XX

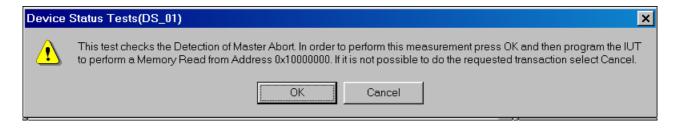
In this group there are three transactions to be executed requiring IUT interactions. These transactions are initiated by the messages indicated below:



Parity Error test



Master Detection of Target Abort



Master Abort due to Target not responding

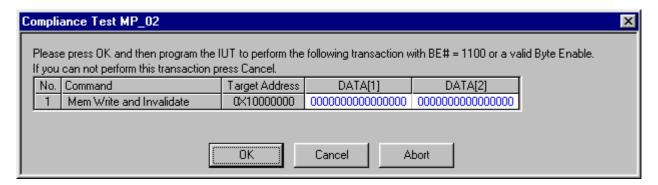
As you see, the required transaction is a memory read from address 0x10000000H. This address is found by TA660 as a free address in memory space.



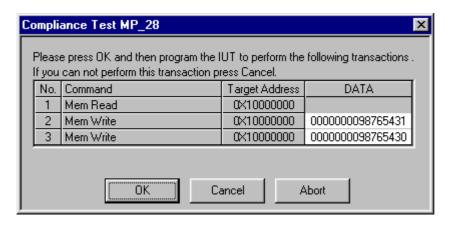
MP_XX General Component Protocol checklist(master)

Most requests are for only one transaction as indicated here, these transactions may be a single word or a burst transfer. In this example a memory write and invalidate command with two data phases is requested.

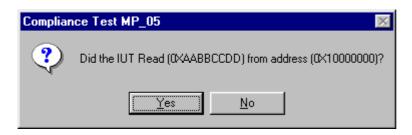
The user may change the data in the white fields. For 32 bit bus set the upper bits to 000000000.



Some requests require several transactions. In this example first a memory read and then two memory writes with different data are requested.



Sometimes the user is requested to confirm the result at the end of the test.





MP Tests

General Component Protocol checklist (master)

Below are the list of requested transactions and their corresponding tests.

Please note that the addresses shown in the examples are based on the test setup, your system may result different addresses. Be sure to do test 1.09 to see what the addresses are free for each Memory, I/O and Configuration spaces.

Some of MP tests are interrelated, These tests are:

- 1. MP_06 MP_07 MP_14 MP_15 MP_16
- 2. MP_24 MP_25
- 3. MP_28 MP_29

The required transactions for each set of tests are the same, thus once one of these tests is executed and the required transaction is performed there will be no message for the next test(s) to perform a transaction. For example to execute test MP_14 only, a message will ask for executing a memory read command with three data phases. But if tests MP_06 or MP_07 have been executed prior to MP_14 the software will not require the memory read transaction again when MP_14 is to be executed.

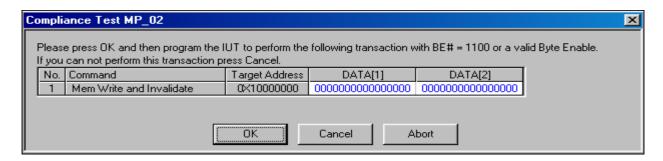
There is no priority for which test to be executed first. For example MP_25 may be executed first and then MP_24, and the software will only requests the transaction to be performed for the first test.

It should be noted that the title of the message box is always includes the name of the first test in the group, so even only MP_25 is executed the title will be "Compliance Test MP_24".



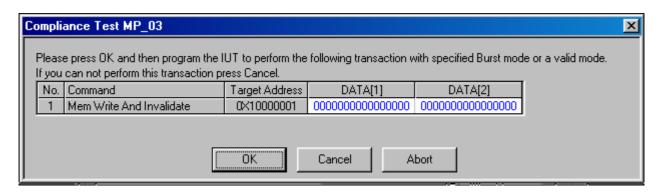
MP_02 IUT always asserts all byte enables during each data phase of a Memory Write Invalidate cycle. (3.1.1)

In this test a memory write and invalidate command with two data phases must be executed by IUT.



MP_03 IUT always uses Linear Burst Ordering for Memory Write Invalidate cycles. (3.1.1)

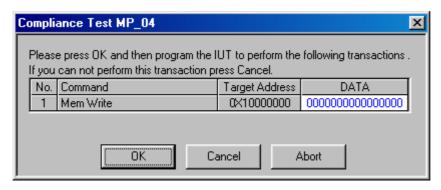
Like previous test a memory write and invalidate command with two data phases must be executed. The memory address of this test is incremented by one, e.g. 10000001H.





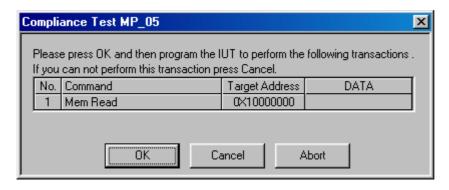
• MP_04 IUT always drives IRDY# when data is valid during a write transaction. (3.2.1)

In this test a memory write command with one data phase must be executed by IUT.



MP_05
 IUT only transfers data when both IRDY# and TRDY# are asserted on the same rising clock edge. (3.2.1)

In this test a memory read command with one data phase must be executed by IUT.

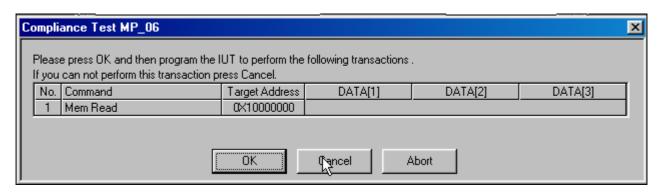




• MP_06

Once the IUT asserts IRDY# it never changes FRAME# until the current data phase completes. (3.2.1)

In this test a memory read command with three data phases must be executed by IUT.



• MP_07

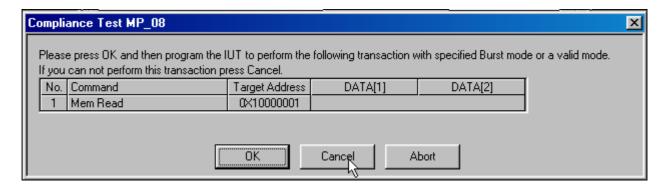
Once the IUT asserts IRDY# it never changes IRDY# until the current data phase completes. (3.2.1)

Part of MP_06 test group.

MP_08

IUT never uses reserved burst ordering (AD(1:0)=B'01'). (3.2.2)

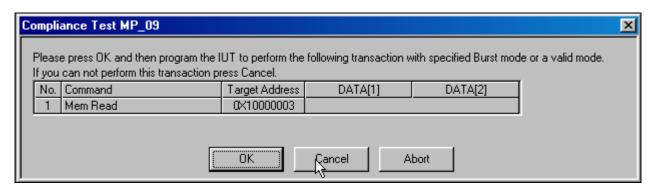
In this test a memory read command with two data phases must be executed by IUT. The memory address of this test is incremented by one, e.g. 10000001H.





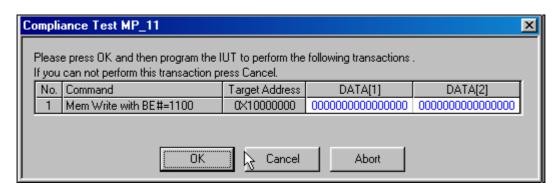
• MP_09 IUT never uses reserved burst ordering (AD(1:0)=B'11'). (3.2.2)

In this test a memory read command with two data phases must be executed by IUT. The memory address of this test is incremented by three, e.g. 10000003H.



• MP_11 The IUT AD lines are driven to stable values during every address and data phase. (3.2.4)

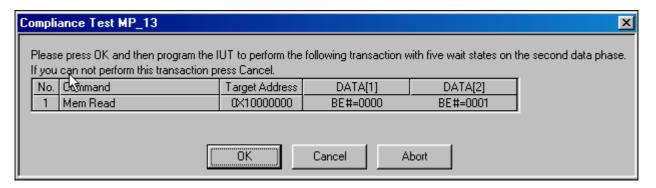
In this test a memory write command with two data phases must be executed by IUT. The CBE#[3:0] in the data phases must be 1100B.





MP_13
 The IUT C/BE# lines contain valid Byte Enable information during the entire data phase.
 (3.31)

In this test a memory read command with two data phases must be executed by IUT. The CBE#[3:0] of the first data phase must be 0000B and in the second data phase 0001B.



• MP_14
IUT never de-asserts FRAME# unless IRDY# is asserted or will be asserted. (3.3.3.1)

Part of MP_06 test group.

MP 15

IUT never de-asserts IRDY# until at least one clock after FRAME# is de-asserted. (3.3.3.1)

Part of MP_06 test group.

• MP 16

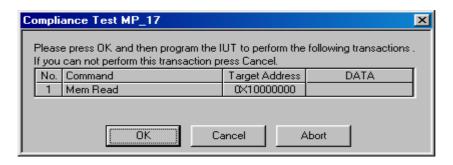
Once the IUT de-asserts FRAME# it never reasserts FRAME# during the same transaction. (3.3.3.1)

Part of MP_06 test group.



• MP_17 IUT never terminates with master abort once target has asserted DEVSEL#. (3.3.3.1)

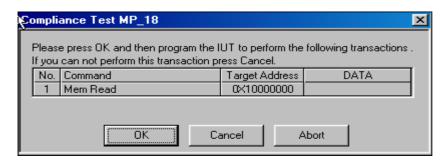
In this test a memory read command with one data phase must be executed by IUT.



• MP_18

IUT never signals master abort earlier than 5 clocks after FRAME# was first sampled asserted. (3.3.3.1)

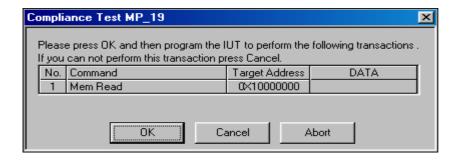
In this test a memory read command with one data phase must be executed by IUT.



• MP_19

IUT always repeats an access exactly as the original when terminated by retry. (3.3.3.2.2)

In this test a memory read command with one data phase must be executed by IUT.





MP_20 IUT never starts cycle unless GNT# is asserted. (3.4.1)

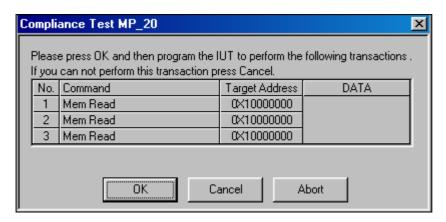
This test requires the IUT to be plugged on top of TA660. Therefore this test can only be done with PCI analyzers and not CPCI. MP_20 will not be executed by the software when user is using TA600C.

Three memory read commands with one data phase for each is requested to check for IUT FRAME# assertion only after GNT# is asserted.

In this test, first the following message is shown:



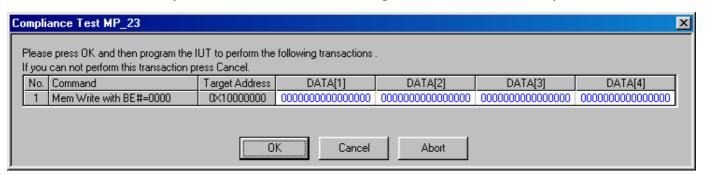
And then the following message is displayed requesting the data transfer.





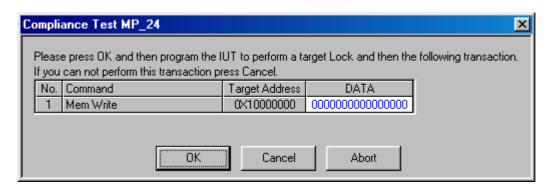
• MP_23 IUT always asserts IRDY# within eight clocks on all data phases. (3.5.2)

In this test a memory write command with four data phases must be executed by IUT.



• MP_24 IUT always begins lock operation with a read transaction. (3.6)

In this test a memory write command with one data phase must be executed by IUT.



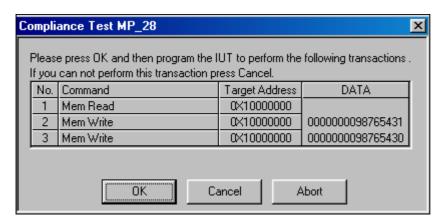
MP_25

Part of MP_24 test group.



MP_28 IUT always drives PAR within one clock of C/BE# and AD being driven. (3.8.1)

In this test three transactions must be executed by IUT all with one data phase. The first transaction is a memory read, the second is a memory write with data equal to 98765431H and the third is a memory write with data equal to 98765430H.



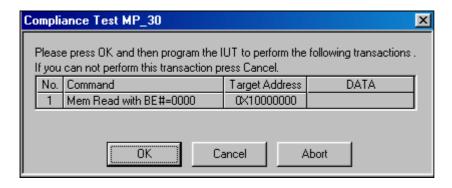
MP_29

Part of MP_28 test group.

• MP 30

IUT always drives PERR# (when enabled) active two clocks after data when data parity error is detected. (3.8.2.1)

In this test a memory read command with one data phase must be executed by IUT.

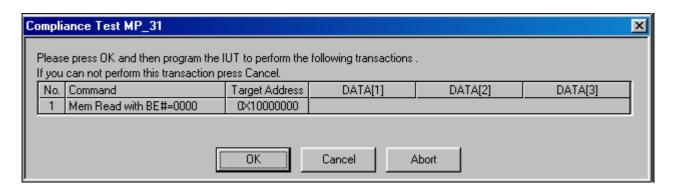




• MP_31

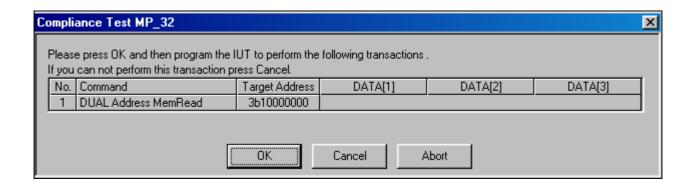
IUT always drives PERR# (when enabled) for a minimum of 1 clock for each data phase that a parity error is detected. (3.8.2.1)

In this test a memory read command with three data phases must be executed by IUT.



• MP_32 IUT always holds FRAME# asserted for cycle following DUAL command. (3.10.1)

In this test dual address cycle is tested thus the address size must be 64-bit. The low 32-bit is the free memory address found by TA660 and the high 32-bit is the constant value 0000003bH. The requested transaction has one data phase.

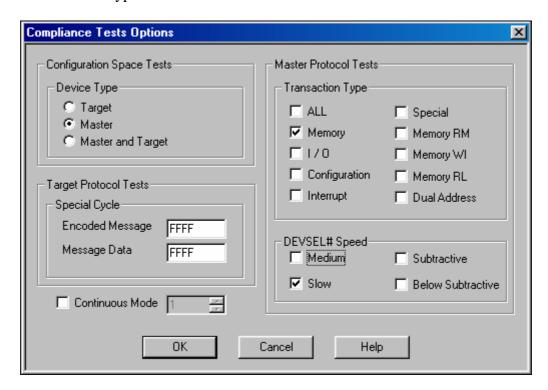




Component Protocol checklist for a master device

1.01 Tests

It is highly recommended that at the beginning the users select only one "Transaction Type" and one "DEVSEL# Speed" to be sure they can execute all the steps correctly and efficiently before enabling more Transaction Types. In some cases each added Transaction adds about 16 tests.



Please note that not all devices are designed to perform all transactions, the user is expected to be familiar with the specification of the device and enable only the appropriate tests.

There are four sets of transactions that may be executed in these tests, if all the selections have been made in the options. Otherwise only the selected categories will be tested.

The first set is a memory read command followed by a memory write command both with one or more data phases.

The second set is an I/O read followed by an I/O write command both with one or more data phases.

The third set is a configuration read followed by a configuration write command both with one or more data phases.

Compliance Test

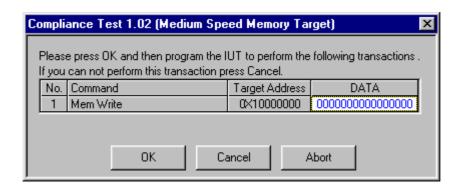


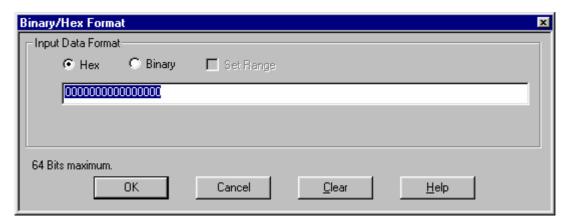
The last set includes some single commands. These commands are:

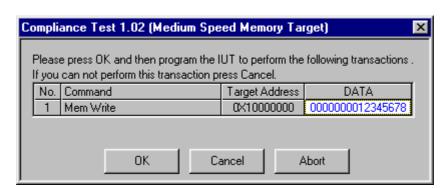
- 1. Memory Read Multiple
- 2. Memory Read Line
- 3. Memory Write & Invalidate
- 4. Special Cycle

The first three commands may have one or more data phases.

In all sets the data to be written by IUT can be changed. For example user may write 12345678H in the memory write command of test 1.02 by selecting the data field and changing the data.





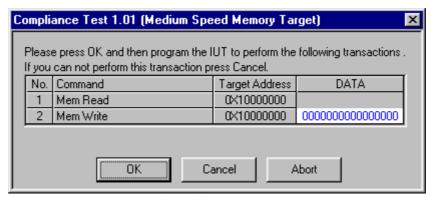




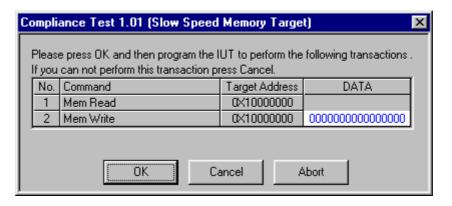


• 1.01 PCI DEVICE SPEED (AS INDICATED BY DEVSEL#) TEST

There are four sets of transactions that must be executed in this test. The first set is a memory read command followed by a memory write command both with one data phase, this set is repeated four times. Then the second set is an I/O read followed by an I/O write command both with one data phase, this set is repeated two times on active motherboards (like computer systems) or four times on passive boards because. Please note on active boards the tests for subtractive and below subtractive I/O target speed can not be executed since the processor or the bridge may respond. The third set is a configuration read followed by a configuration write command both with one data phase. This set is repeated four times. The last section is a special cycle command which is not repeated.

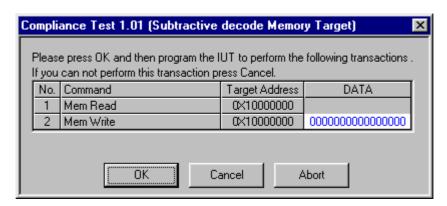


Medium Speed Memory

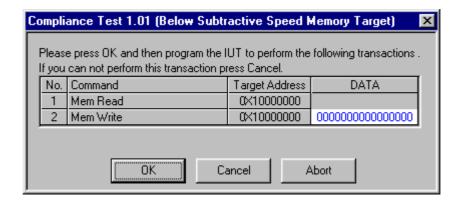


Slow Speed Memory

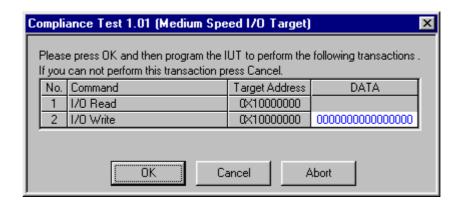




Subtractive Speed Memory

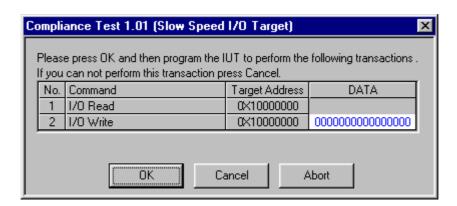


Below Subtractive Speed Memory

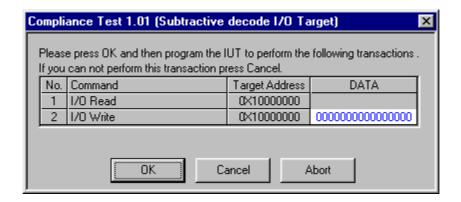


Medium Speed I/O

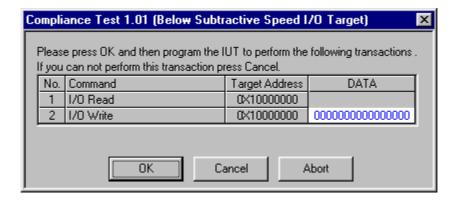




Slow Speed I/O

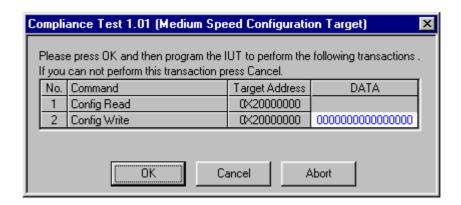


Subtractive Speed I/O

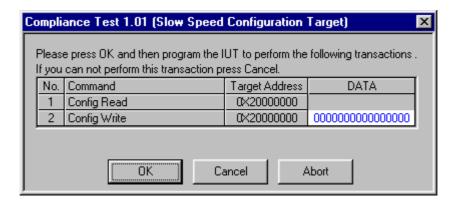


Below Subtractive Speed I/O

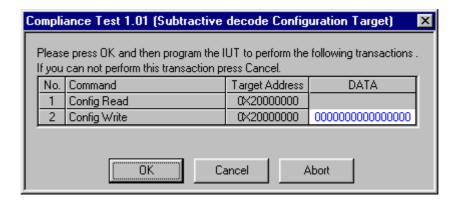




Medium Speed Configuration

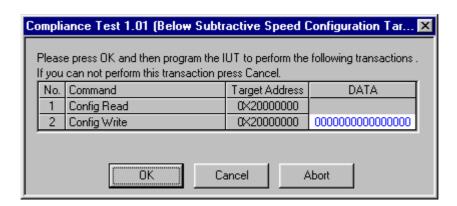


Slow Speed Configuration

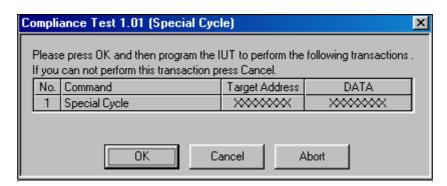


Subtractive Speed Configuration





Below Subtractive Speed Configuration



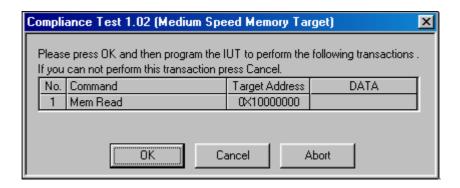
Special Cycle Test



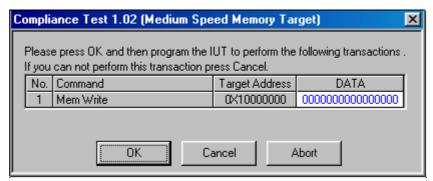
1.02

PCI BUS SINGLE DATA PHASE TARGET ABORT CYCLES

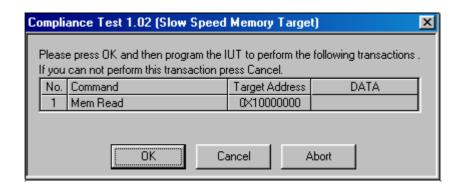
The transactions of this section are similar to the previous section (1.01) with the exception that the memory and configuration sets are repeated three times instead of four, the I/O set is repeated two times on active boards and three times on passive boards and the special cycle is not needed.



Medium Speed Memory Read

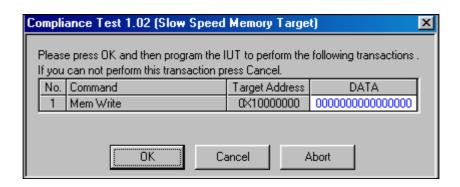


Medium Speed Memory Write

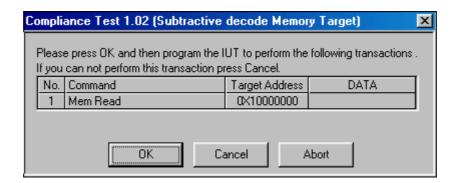


Slow Speed Memory Read

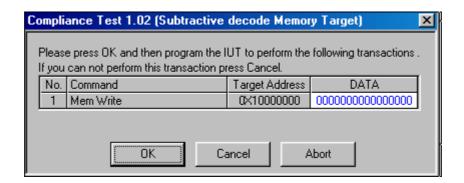




Slow Speed Memory Write

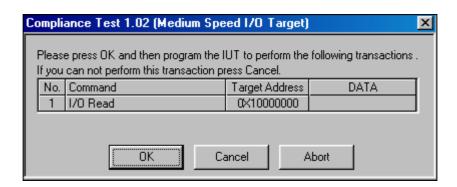


Subtractive Speed Memory Read

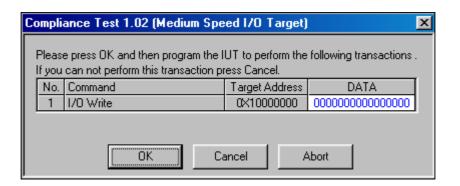


Subtractive Speed Memory Write

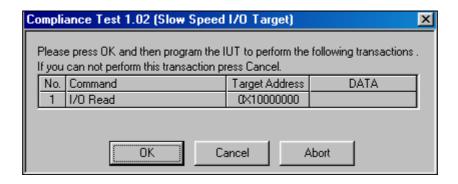




Medium Speed I/O Read

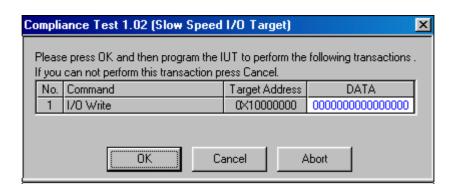


Medium Speed I/O Write

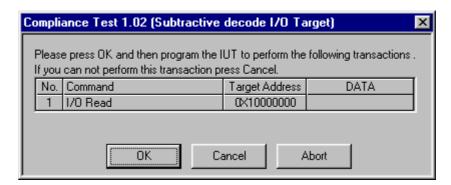


Slow Speed I/O Read

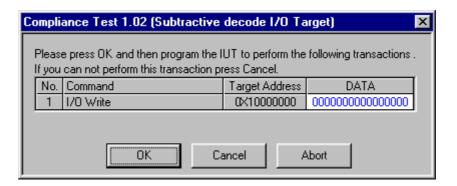




Slow Speed I/O Write

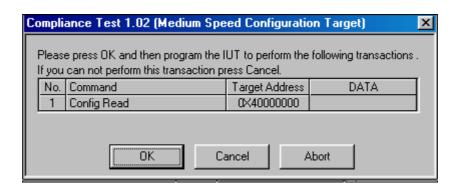


Subtractive Speed I/O Read

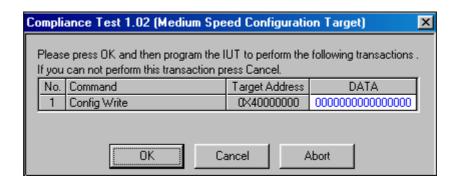


Subtractive Speed I/O Write

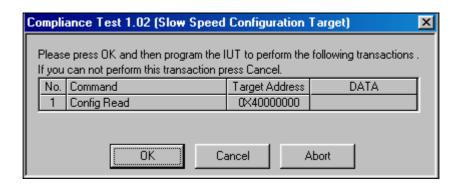




Medium Speed Configuration Read

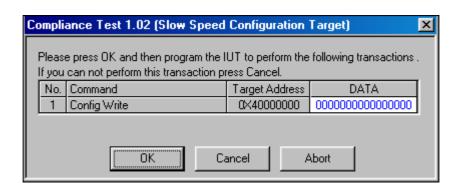


Medium Speed Configuration Write

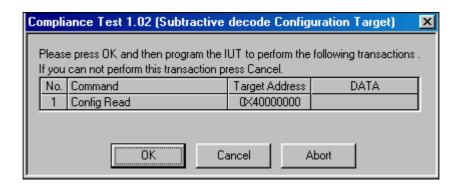


Slow Speed Configuration Read

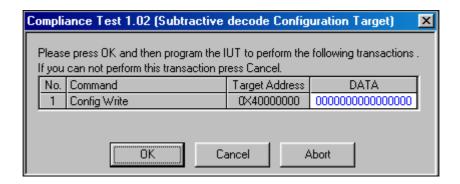




Slow Speed Configuration Write



Subtractive Speed Configuration Read

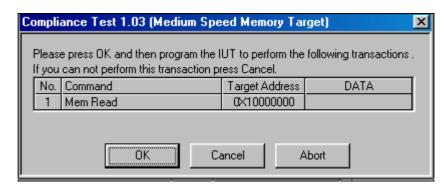


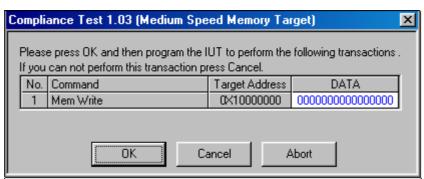
Subtractive Speed Configuration Write

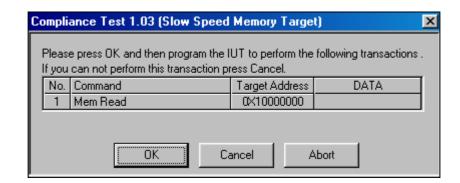


• 1.03 PCI BUS SINGLE DATA PHASE RETRY CYCLES

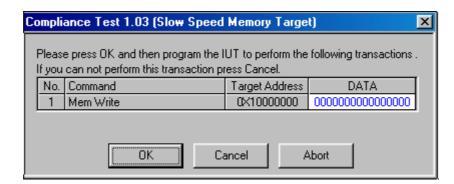
The transactions of this section are similar to the previous section (1.02) with the exception that sometimes a confirmation message is shown. The software will test for master retry.

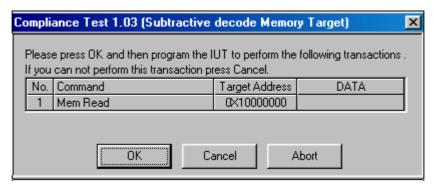


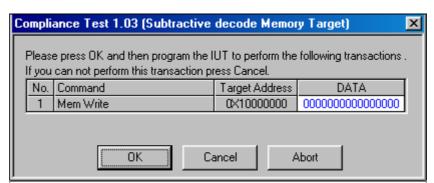


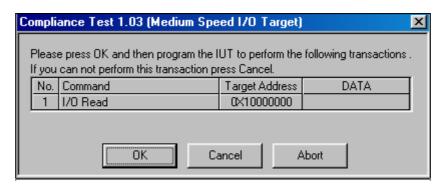




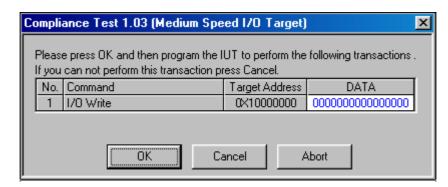


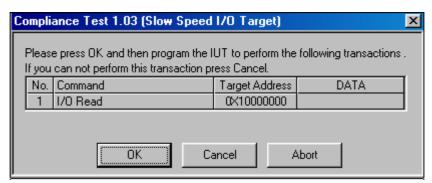


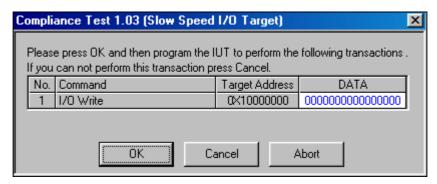


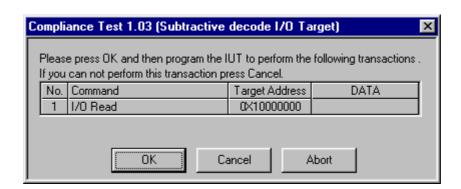




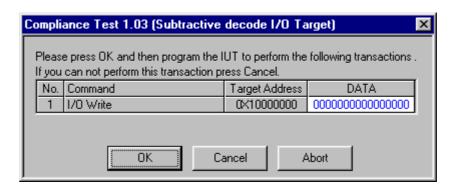


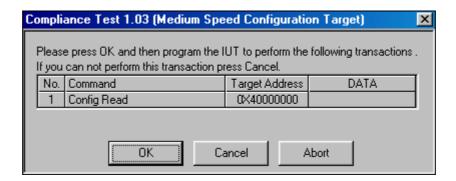


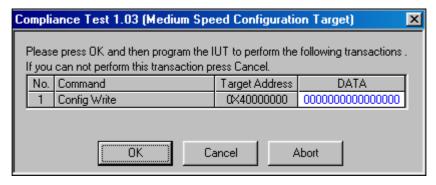


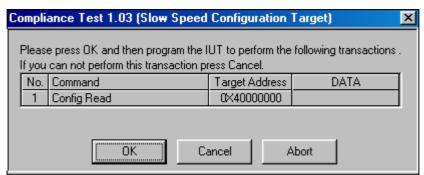




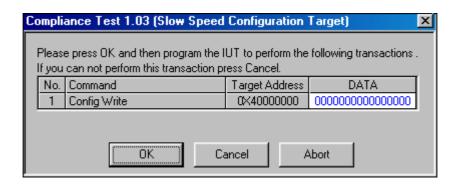


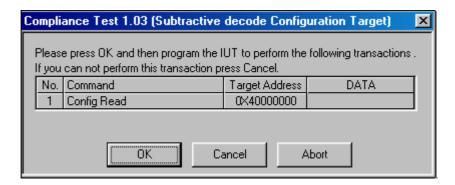


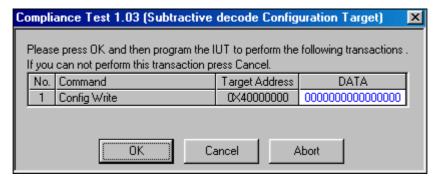








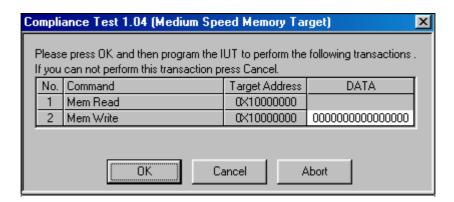


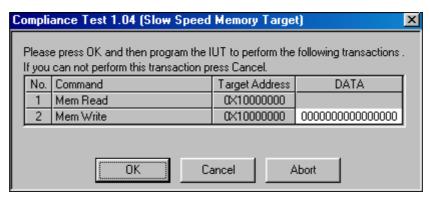


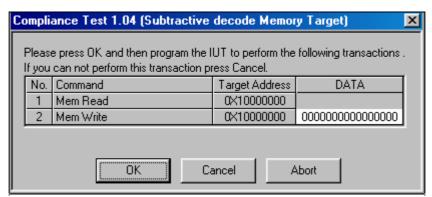


• 1.04 PCI BUS SINGLE DATA PHASE DISCONNECT CYCLES

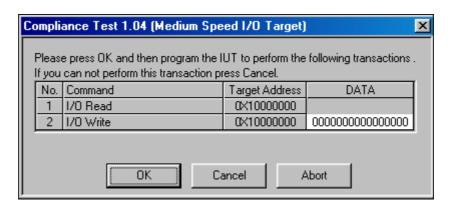
The transactions of this section are similar to the section 1.02. The software will test for master disconnects.

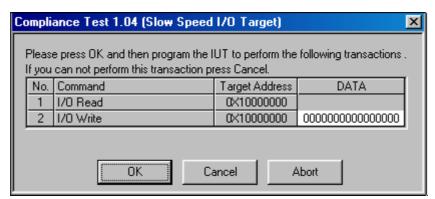


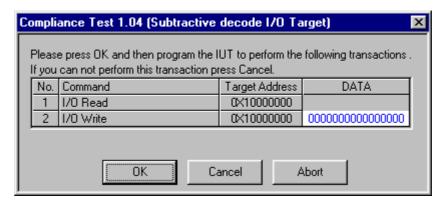


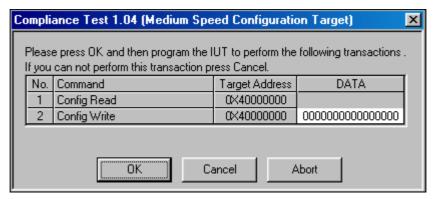




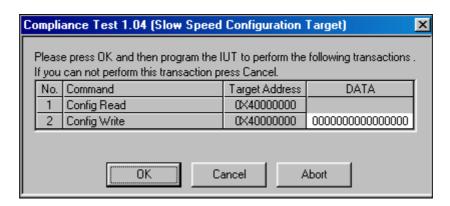


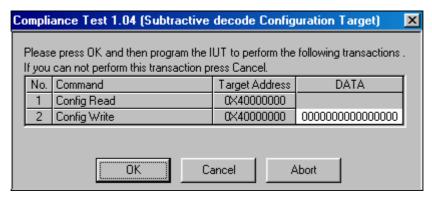








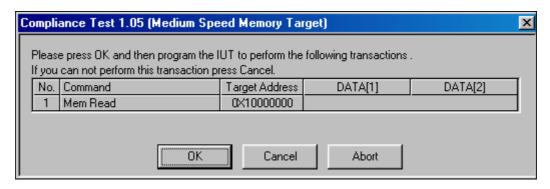


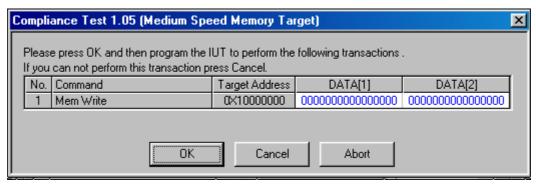


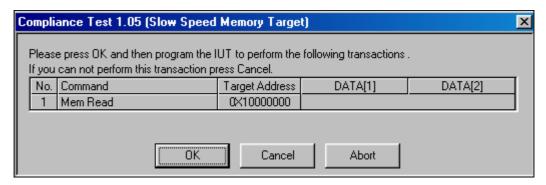


• 1.05 PCI BUS MULTI-DATA PHASE TARGET ABORT CYCLES

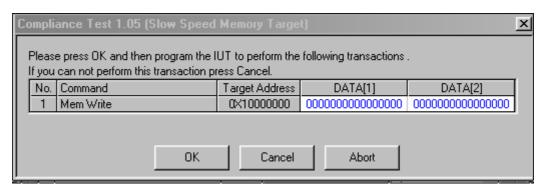
There are five sets of transactions that must be executed in this test. The first set is a memory read command followed by a memory write command both with two data phases and the data of write command is 00000000H. This set is repeated three times. The second set is a configuration read followed by a configuration write command both with two data phases and the data of write command is 00000000H. This set is repeated three times. The third section is a memory read multiple command with three data phases that is repeated three times. The fourth section is a memory read line command with three data phases that is repeated three times. The last section is a memory write & invalidate command with three data phases (data value equal to 00000000H) that is repeated three times.

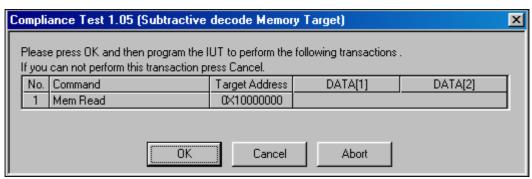


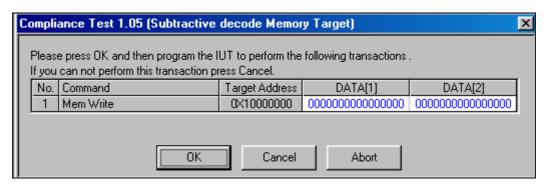


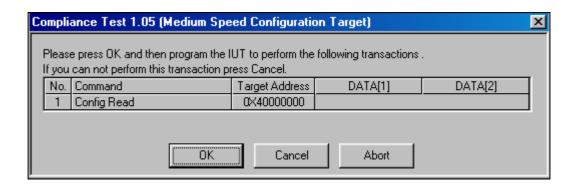




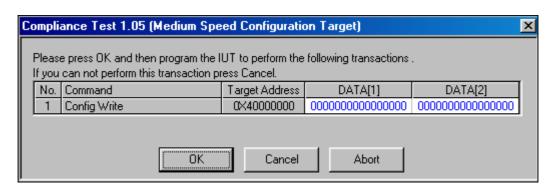


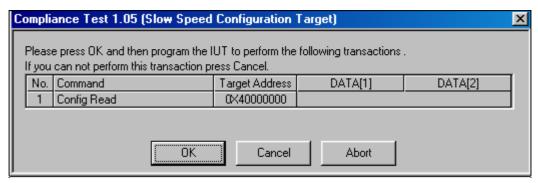


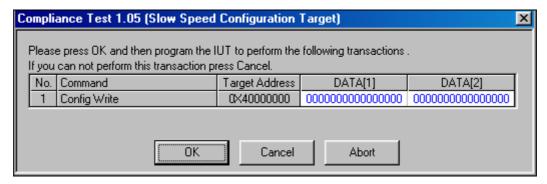


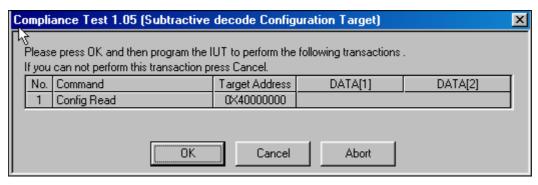




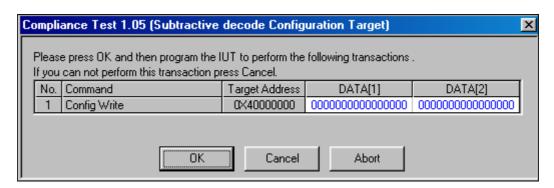


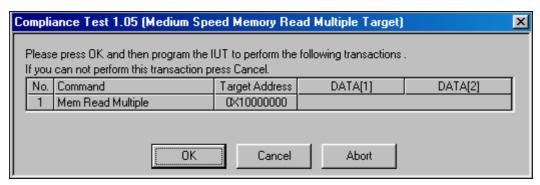


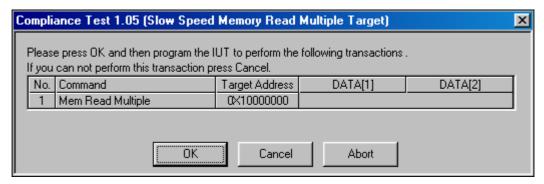


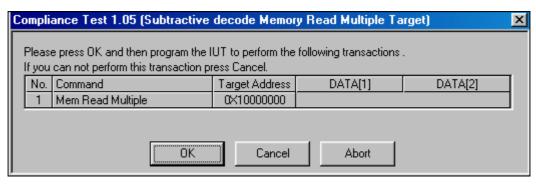




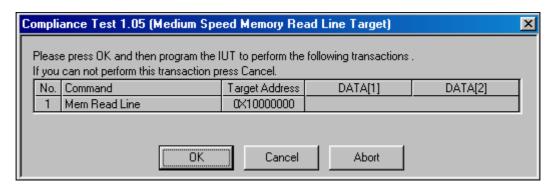


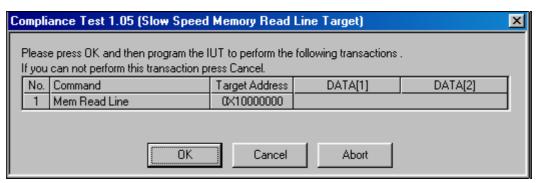


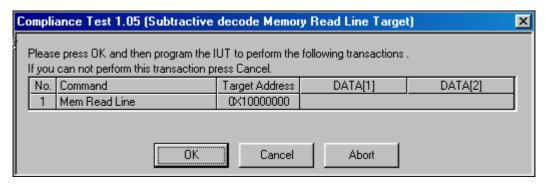


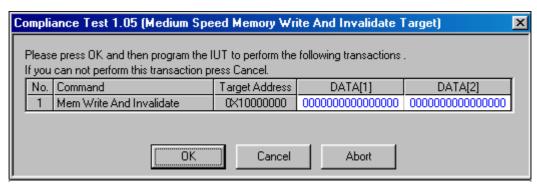




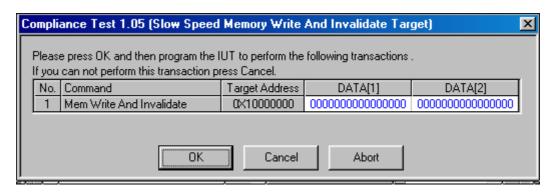


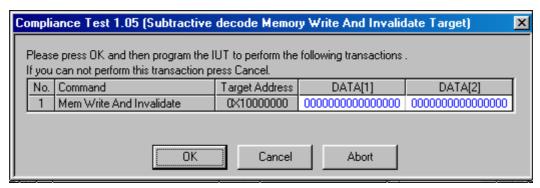








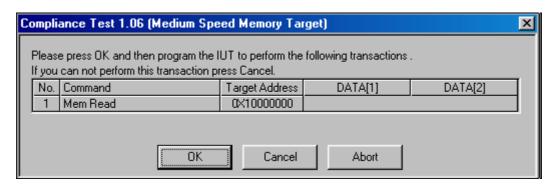


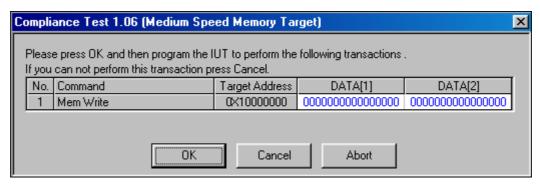


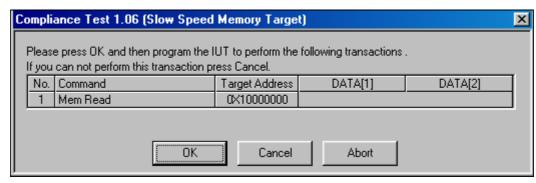


• 1.06 PCI BUS MULTI-DATA PHASE RETRY CYCLES

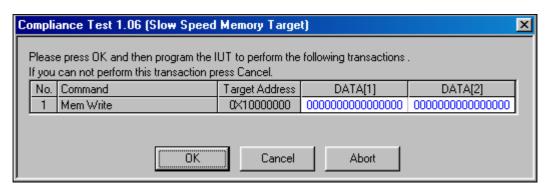
The transactions of this section are similar to the previous section (1.05) The software will test for master retry, some messages include confirmation from the user.

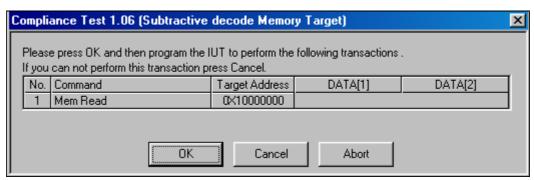


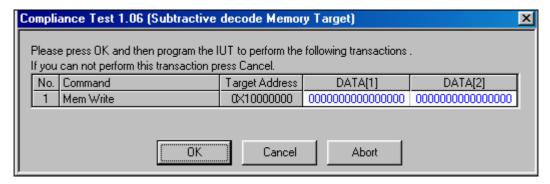


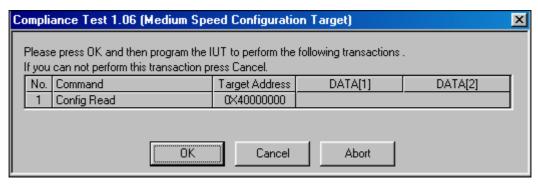




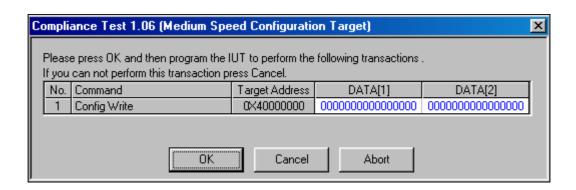


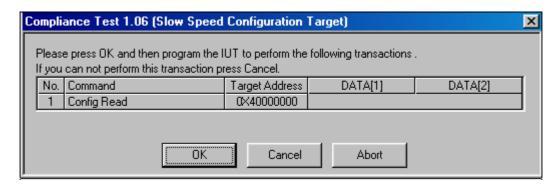


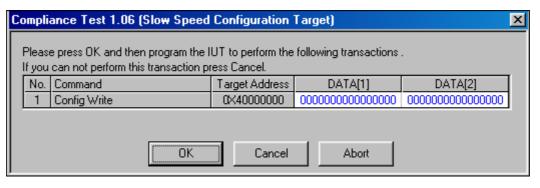


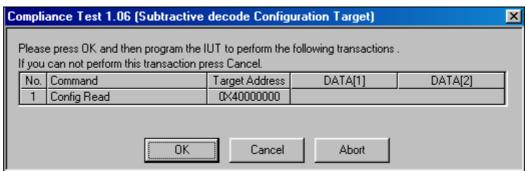




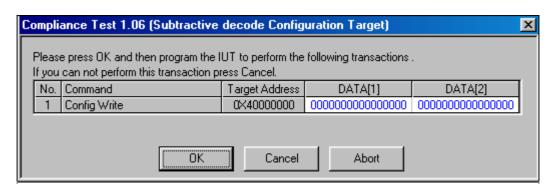


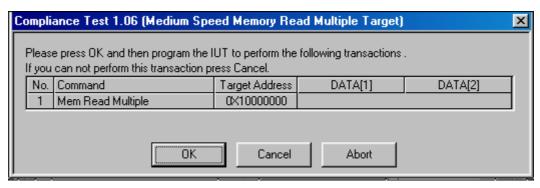


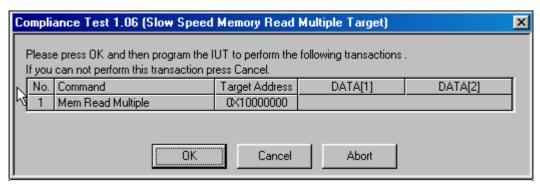


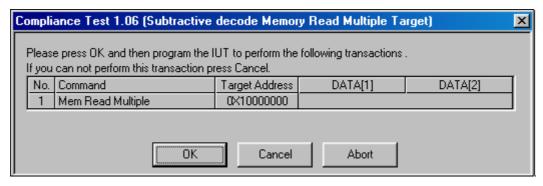




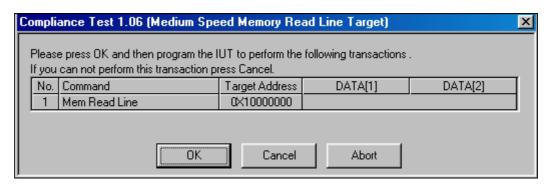


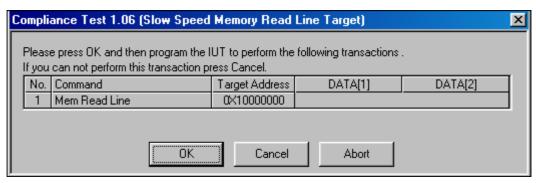


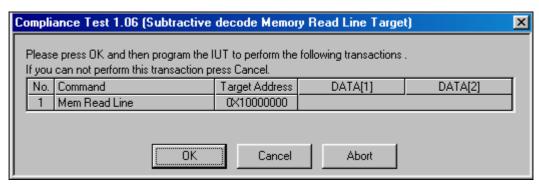


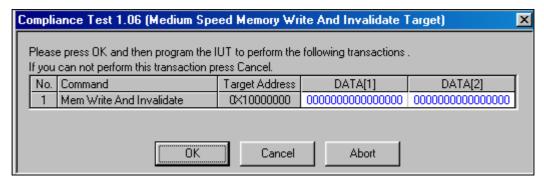




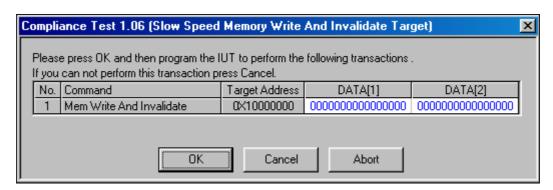


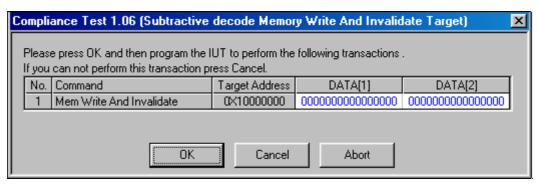








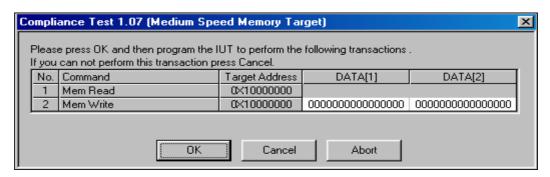


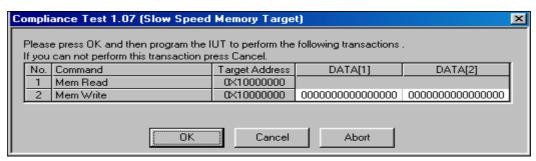


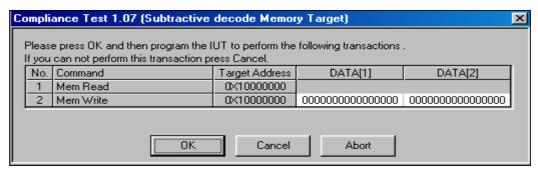


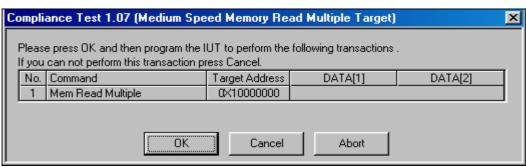
• 1.07 PCI BUS MULTI-DATA PHASE DISCONNECT CYCLES

The transactions of this section are similar to the previous section (1.06). The software will test for master disconnects.

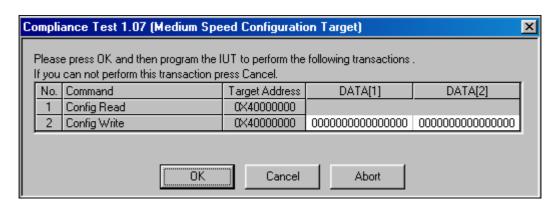


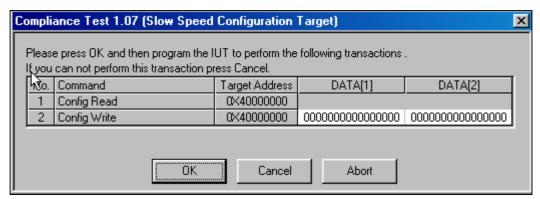


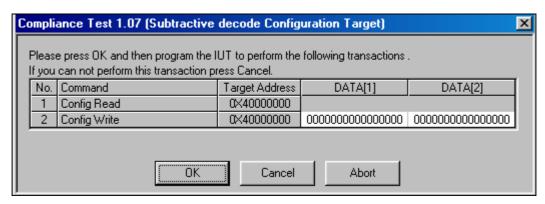




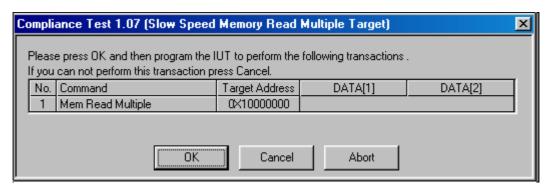


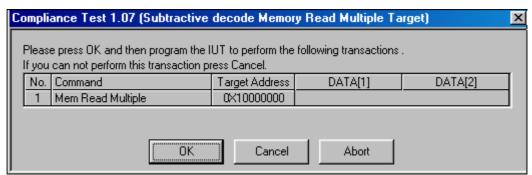


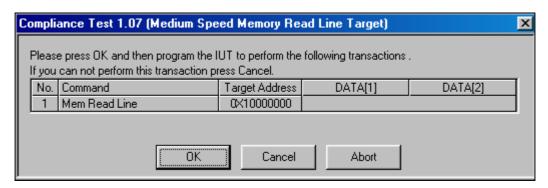


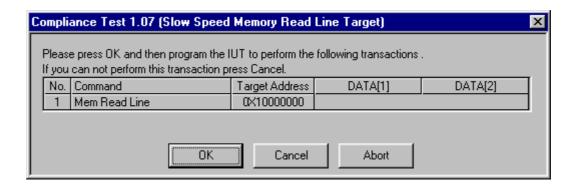




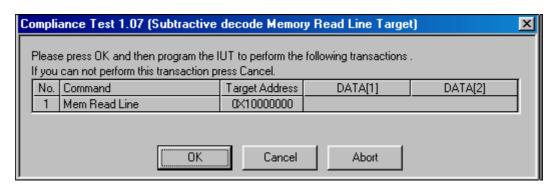


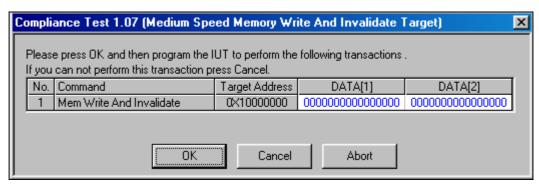


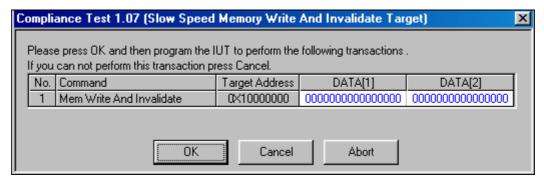


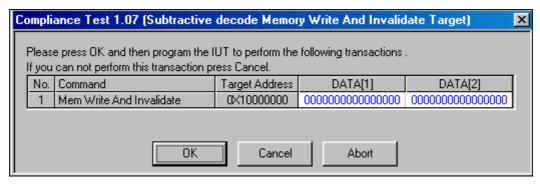










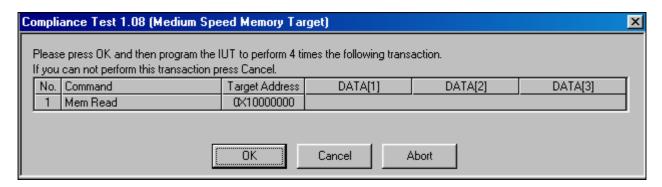


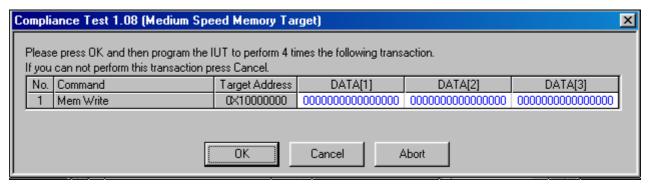


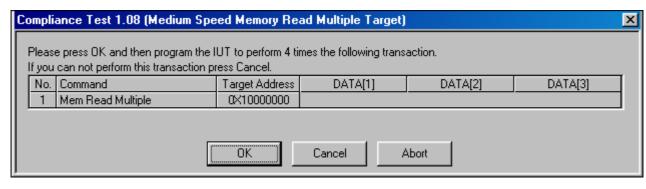
• 1.08

PCI BUS MULTI-DATA PHASE & TRDY# CYCLES

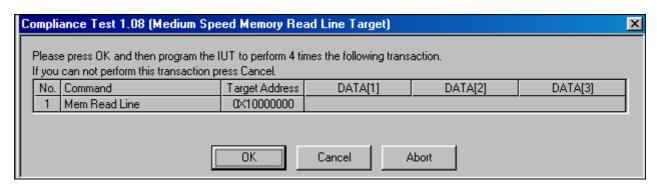
In this test five transactions must be executed. The first is a memory read, the second is a memory write, the third is a memory read multiple, the fourth is a memory read line and the last is a memory write & invalidate. All transactions have three data phases.

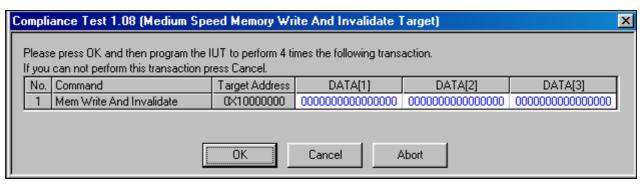








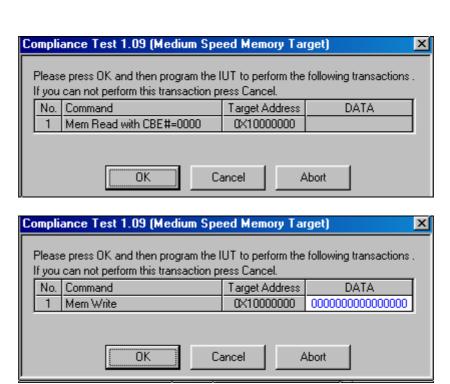


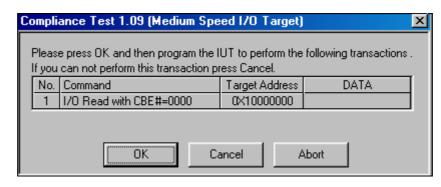




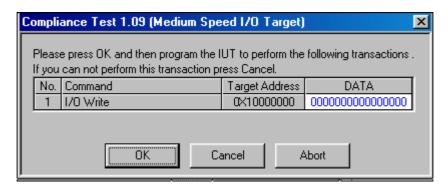
• 1.09 PCI BUS DATA PARITY ERROR SINGLE CYCLES

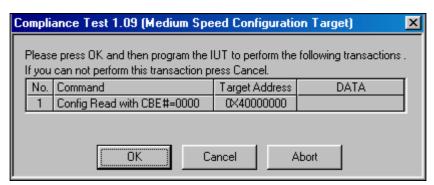
In this test six transactions must be executed. The first is a memory read, the second is a memory write, the third is an I/O read, the fourth is an I/O write, the fifth is a configuration read and the last is a configuration write. All transactions have one data phase.

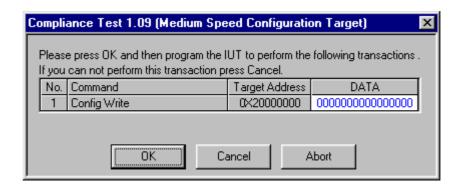








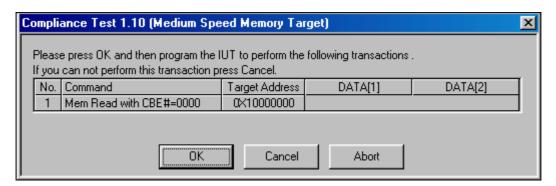


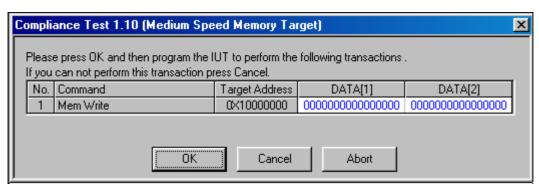


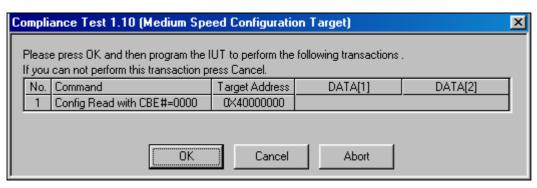
• 1.10 PCI BUS DATA PARITY ERROR MULTI-DATA PHASE CYCLES

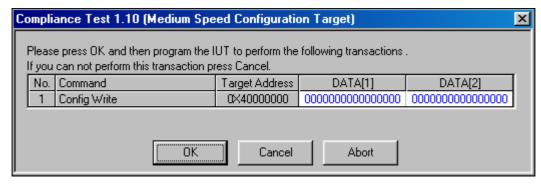
In this test seven transactions must be executed. The first is a memory read, the second is a memory write, the third is a configuration read, the fourth is a configuration write, the fifth is a memory read multiple, the sixth is a memory read line and the last is a memory write & invalidate. All transactions have two data phases.



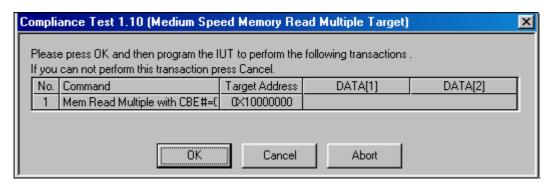


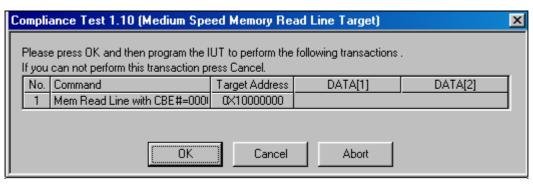


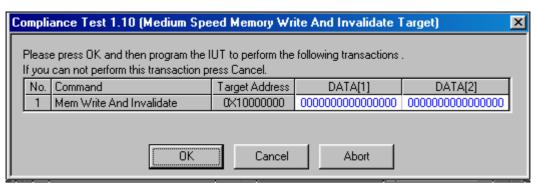












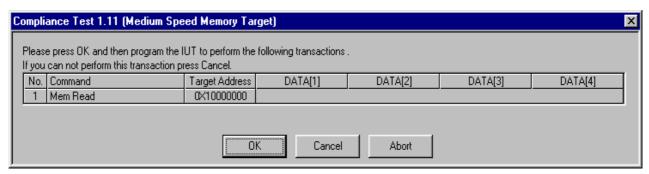


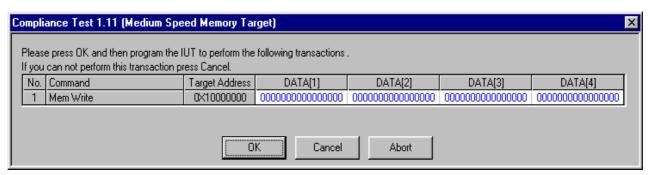
1.11 PCI BUS MASTER TIMEOUT

This test requires the IUT to be plugged on top of TA660. Therefore this test can only be done with PCI analyzers and not CPCI. The 1.11 test will not be executed by the software when user is using TA600C.

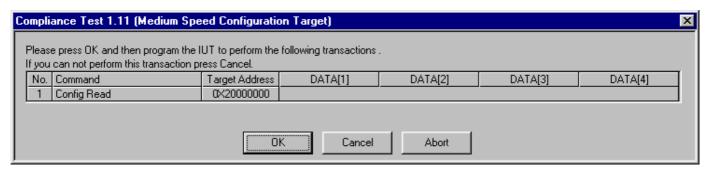
In this test the IUT must be plugged on the top connector of TA660. The requested transactions are similar to the test 1.10 with the exception that each transaction has four data phases.

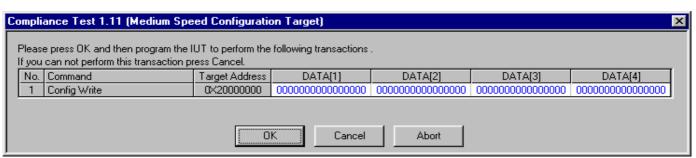


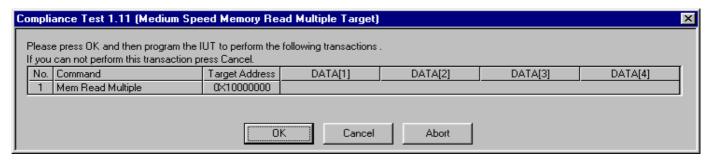


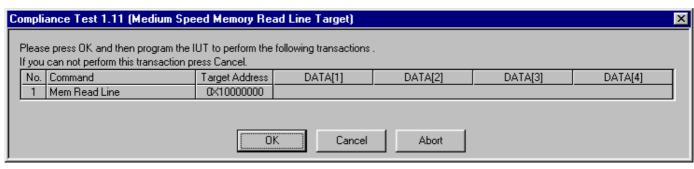




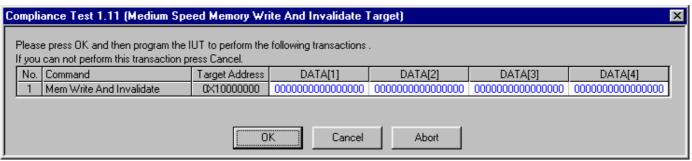












Below is a summary table of the MP_XX transactions:

Test	Command	Burst size	Data(s)	CBE#(s)
MP_02	Mem Write & Inv.	2	00000000-00000000	0000-0000
MP_03	Mem Write & Inv.	2	00000000-00000000	0000-0000
MP_04	Mem Write	1	00000000	0000
MP_05	Mem Read	1	00000000	0000
MP_06	Mem Read	3	00000000-00000000	0000-0000
			00000000	0000
MP_07	Mem Read	3	00000000-00000000	0000-0000
			00000000	0000
MP_08	Mem Read	2	00000000-00000000	0000-0000
MP_09	Mem Read	2	00000000-00000000	0000-0000
MP_11	Mem Write	2	00000000-00000000	1100-1100
MP_13	Mem Read	2	00000000-00000000	0000-0001
MP_14	Mem Read	3	00000000-00000000	0000-0000
			00000000	0000
MP_15	Mem Read	3	00000000-00000000	0000-0000
			00000000	0000
MP_16	Mem Read	3	00000000-00000000	0000-0000
			00000000	0000
MP_17	Mem Read	1	00000000	0000
MP_18	Mem Read	1	00000000	0000
MP_19	Mem Read	1	00000000	0000
	Mem Read (1)	1	00000000	0000
MP_20	Mem Read (2)	1	00000000	0000
	Mem Read (3)	1	00000000	0000
MP_23	Mem Write	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
MP_24	Mem Write	1	00000000	0000
MP_25	Mem Write	1	00000000	0000
	Mem Read (1)	1	00000000	0000
MP_28	Mem Write (2)	1	98765431	0000
	Mem Write (3)	1	98765430	0000
	Mem Read (1)	1	00000000	0000

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MP_29	Mem Write (2)	1	98765431	0000
	Mem Write (3)	1	98765430	0000
MP_30	Mem Read	1	00000000	0000
MP_31	Mem Read	3	00000000-00000000	0000-0000
			00000000	0000
MP_32	Dual Address	1	00000000	0000

Below is a summary table of the 1.XX transactions.

The transactions with red color must be executed only when the test environment is a passive motherboard:

Test	Command	Burst size	Data(s)	CBE#(s)
1.01	Mem Read (1)	1	00000000	0000
	Mem Write (2)	1	00000000	0000
	Mem Read (3)	1	00000000	0000
	Mem Write (4)	1	00000000	0000
	Mem Read (5)	1	00000000	0000
	Mem Write (6)	1	00000000	0000
	Mem Read (7)	1	00000000	0000
	Mem Write (8)	1	00000000	0000
	I/O Read (9)	1	00000000	0000
	I/O Write (10)	1	00000000	0000
	I/O Read (11)	1	00000000	0000
	I/O Write (12)	1	00000000	0000
	I/O Read (12.1)	1	00000000	0000
	I/O Write (12.2)	1	00000000	0000
	I/O Read (12.3)	1	00000000	0000
	I/O Write (12.4)	1	00000000	0000
	Config Read (13)	1	00000000	0000
	Config Write (14)	1	00000000	0000
	Config Read (15)	1	00000000	0000
	Config Write (16)	1	00000000	0000
	Config Read (17)	1	00000000	0000
	Config Write (18)	1	00000000	0000
	Config Read (19)	1	00000000	0000
	Config Write (20)	1	00000000	0000
	Special Cycle	1	FFFFFFF	0000



Test	Command	Burst size	Data(s)	CBE#(s)
1.02	Mem Read (1)	1	00000000	0000
	Mem Write (2)	1	00000000	0000
	Mem Read (3)	1	00000000	0000
	Mem Write (4)	1	00000000	0000
	Mem Read (5)	1	00000000	0000
	Mem Write (6)	1	00000000	0000
	I/O Read (7)	1	00000000	0000
	I/O Write (8)	1	00000000	0000
	I/O Read (9)	1	00000000	0000
	I/O Write (10)	1	00000000	0000
	I/O Read (10.1)	1	00000000	0000
	I/O Write (10.2)	1	00000000	0000
	Config Read (11)	1	00000000	0000
	Config Write (12)	1	00000000	0000
	Config Read (13)	1	00000000	0000
	Config Write (14)	1	00000000	0000
	Config Read (15)	1	00000000	0000
	Config Write (16)	1	00000000	0000



Test	Command	Burst size	Data(s)	CBE#(s)
1.03	Mem Read (1)	1	00000000	0000
	Mem Write (2)	1	00000000	0000
	Mem Read (3)	1	00000000	0000
	Mem Write (4)	1	00000000	0000
	Mem Read (5)	1	00000000	0000
	Mem Write (6)	1	00000000	0000
	I/O Read (7)	1	00000000	0000
	I/O Write (8)	1	00000000	0000
	I/O Read (9)	1	00000000	0000
	I/O Write (10)	1	00000000	0000
	I/O Read (10.1)	1	00000000	0000
	I/O Write (10.2)	1	00000000	0000
	Config Read (11)	1	00000000	0000
	Config Write (12)	1	00000000	0000
	Config Read (13)	1	00000000	0000
	Config Write (14)	1	00000000	0000
	Config Read (15)	1	00000000	0000
	Config Write (16)	1	00000000	0000
1.04	Mem Read (1)	1	00000000	0000
	Mem Write (2)	1	00000000	0000
	Mem Read (3)	1	00000000	0000
	Mem Write (4)	1	00000000	0000
	Mem Read (5)	1	00000000	0000
	Mem Write (6)	1	00000000	0000
	I/O Read (7)	1	00000000	0000
	I/O Write (8)	1	00000000	0000
	I/O Read (9)	1	00000000	0000
	I/O Write (10)	1	00000000	0000
	I/O Read (10.1)	1	00000000	0000
	I/O Write (10.2)	1	00000000	0000
	Config Read (11)	1	00000000	0000
	Config Write (12)	1	00000000	0000
	Config Read (13)	1	00000000	0000
	Config Write (14)	1	00000000	0000
	Config Read (15)	1	00000000	0000
	Config Write (16)	1	00000000	0000



Test	Command	Burst size	Data(s)	CBE#(s)
1.05	Mem Read (1)	2	00000000-00000000	0000-0000
	Mem Write (2)	2	0000000-00000000	0000-0000
	Mem Read (3)	2	00000000-00000000	0000-0000
	Mem Write (4)	2	00000000-00000000	0000-0000
	Mem Read (5)	2	00000000-00000000	0000-0000
	Mem Write (6)	2	0000000-00000000	0000-0000
	Config Read (7)	2	0000000-00000000	0000-0000
	Config Write (8)	2	0000000-00000000	0000-0000
	Config Read (9)	2	00000000-00000000	0000-0000
	Config Write (10)	2	00000000-00000000	0000-0000
	Config Read (11)	2	00000000-00000000	0000-0000
	Config Write (12)	2	0000000-00000000	0000-0000
	Mem Read Mul.(13)	2	00000000-00000000	0000-0000
	Mem Read Mul.(14)	2	0000000-00000000	0000-0000
	Mem Read Mul.(15)	2	00000000-00000000	0000-0000
	Mem Read Line.(16)	2	0000000-00000000	0000-0000
	Mem Read Line.(17)	2	0000000-00000000	0000-0000
	Mem Read Line.(18)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(19)	2	0000000-00000000	0000-0000
	Mem Write&Inv.(20)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(21)	2	00000000-00000000	0000-0000
1.06	Mem Read (1)	2	00000000-00000000	0000-0000
	Mem Write (2)	2	00000000-00000000	0000-0000
	Mem Read (3)	2	00000000-00000000	0000-0000
	Mem Write (4)	2	00000000-00000000	0000-0000
	Mem Read (5)	2	00000000-00000000	0000-0000
	Mem Write (6)	2	00000000-00000000	0000-0000
	Config Read (7)	2	00000000-00000000	0000-0000
	Config Write (8)	2	00000000-00000000	0000-0000
	Config Read (9)	2	00000000-00000000	0000-0000
	Config Write (10)	2	00000000-00000000	0000-0000
	Config Read (11)	2	00000000-00000000	0000-0000
	Config Write (12)	2	00000000-00000000	0000-0000
	Mem Read Mul.(13)	2	00000000-00000000	0000-0000
	Mem Read Mul.(14)	2	00000000-00000000	0000-0000
	Mem Read Mul.(15)	2	00000000-00000000	0000-0000
	Mem Read Line.(16)	2	00000000-00000000	0000-0000
	Mem Read Line.(17)	2	00000000-00000000	0000-0000
	Mem Read Line.(18)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(19)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(20)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(21)	2	00000000-00000000	0000-0000

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Test	Command	Burst size	Data(s)	CBE#(s)
1.07	Mem Read (1)	2	00000000-00000000	0000-0000
	Mem Write (2)	2	00000000-00000000	0000-0000
	Mem Read (3)	2	00000000-00000000	0000-0000
	Mem Write (4)	2	00000000-00000000	0000-0000
	Mem Read (5)	2	00000000-00000000	0000-0000
	Mem Write (6)	2	00000000-00000000	0000-0000
	Config Read (7)	2	00000000-00000000	0000-0000
	Config Write (8)	2	00000000-00000000	0000-0000
	Config Read (9)	2	00000000-00000000	0000-0000
	Config Write (10)	2	00000000-00000000	0000-0000
	Config Read (11)	2	00000000-00000000	0000-0000
	Config Write (12)	2	00000000-00000000	0000-0000
	Mem Read Mul.(13)	2	00000000-00000000	0000-0000
	Mem Read Mul.(14)	2	00000000-00000000	0000-0000
	Mem Read Mul.(15)	2	00000000-00000000	0000-0000
	Mem Read Line.(16)	2	00000000-00000000	0000-0000
	Mem Read Line.(17)	2	00000000-00000000	0000-0000
	Mem Read Line.(18)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(19)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(20)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(21)	2	00000000-00000000	0000-0000
1.08	Mem Read (1)	3	00000000-00000000	0000-0000
			00000000	0000
	Mem Write (2)	3	00000000-00000000	0000-0000
			00000000	0000
	Mem Read Mul.(3)	3	00000000-00000000	0000-0000
			00000000	0000
	Mem Read Line.(4)	3	00000000-00000000	0000-0000
			00000000	0000
	Mem Write&Inv.(5)	3	00000000-00000000	0000-0000
			00000000	0000
1.09	Mem Read (1)	1	00000000	0000
	Mem Write (2)	1	00000000	0000
	I/O Read (3)	1	00000000	0000
	I/O Write (4)	1	00000000	0000
	Config Read (5)	1	00000000	0000
	Config Write (6)	1	00000000	0000



Test	Command	Burst size	Data(s)	CBE#(s)
1.10	Mem Read (1)	2	00000000-00000000	0000-0000
	Mem Write (2)	2	00000000-00000000	0000-0000
	Config Read (3)	2	00000000-00000000	0000-0000
	Config Write (4)	2	00000000-00000000	0000-0000
	Mem Read Mul.(5)	2	00000000-00000000	0000-0000
	Mem Read Line.(6)	2	00000000-00000000	0000-0000
	Mem Write&Inv.(7)	2	00000000-00000000	0000-0000
1.11	Mem Read (1)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
	Mem Write (2)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
	Config Read (3)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
	Config Write (4)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
	Mem Read Mul.(5)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
	Mem Read Line.(6)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000
	Mem Write&Inv.(7)	4	00000000-00000000	0000-0000
			00000000-00000000	0000-0000